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Intel - 5SGXMA5H2F35I2LN Datasheet



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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	46080000
Number of I/O	552
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA, FCBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxma5h2f35i2ln

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Symbol	Description	Devices	Minimum ⁽⁴⁾	Typical	Maximum ⁽⁴⁾	Unit
			0.82	0.85	0.88	
V _{CCR_GXBR}	Receiver analog power supply (right side)		0.87	0.90	0.93	V
(2)	neceiver analog power supply (right side)	ux, uu, ui	0.97	1.0	1.03	v
			1.03	1.05	1.07	
V _{CCR_GTBR}	Receiver analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
			0.82	0.85	0.88	
V _{CCT GXBL}	Transmitter analog newer supply (left side)		0.87	0.90	0.93	V
(2)	Transmitter analog power supply (left side)	un, uo, ui	0.97	1.0	1.03	
			1.03	1.05	1.07	
		GX, GS, GT	0.82	0.85	0.88	V
V _{CCT GXBR}	Transmitter analog power supply (right side)		0.87	0.90	0.93	
(2) _			0.97	1.0	1.03	
			1.03	1.05	1.07	
V_{CCT_GTBR}	Transmitter analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
V_{CCL_GTBR}	Transmitter clock network power supply	GT	1.02	1.05	1.08	V
V _{CCH_GXBL}	Transmitter output buffer power supply (left side)	GX, GS, GT	1.425	1.5	1.575	V
V _{CCH_GXBR}	Transmitter output buffer power supply (right side)	GX, GS, GT	1.425	1.5	1.575	V

Table 7.	Recommended Transceiver Power Supply Operating Conditions for Stratix V GX ,	GS , and GT Devices
(Part 2	of 2)	

Notes to Table 7:

(1) This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.

(2) Refer to Table 8 to select the correct power supply level for your design.

(3) When using ATX PLLs, the supply must be 3.0 V.

(4) This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 8 shows the transceiver power supply voltage requirements for various conditions.

Table 8. Transceiver Power Supply Voltage Requirements

Conditions Core Speed Grade		VCCR_GXB & VCCT_GXB ⁽²⁾	VCCA_GXB	VCCH_GXB	Unit
If BOTH of the following conditions are true:	A11	1.05			
■ Data rate > 10.3 Gbps.	All	1.00			
 DFE is used. 					
If ANY of the following conditions are true ⁽¹⁾ :			3.0		
 ATX PLL is used. 					
■ Data rate > 6.5Gbps.	All	1.0			
■ DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used.				1.5	V
If ALL of the following	C1, C2, I2, and I3YY	0.90	2.5		
 ATX PLL is not used. 					
■ Data rate \leq 6.5Gbps.	C2L, C3, C4, I2L, I3, I3L, and I4	0.85	2.5		
 DFE, AEQ, and EyeQ are not used. 					

Notes to Table 8:

(1) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.

(2) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to either 0.90 V or 0.85 V, they can be shared with the VCC core supply.

DC Characteristics

This section lists the supply current, I/O pin leakage current, input pin capacitance, on-chip termination tolerance, and hot socketing specifications.

Supply Current

Supply current is the current drawn from the respective power rails used for power budgeting. Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.

For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9.	I/O Pin	Leakage	Current for	Stratix V	Devices (1)
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Symbol	Description	Conditions	Min	Тур	Max	Unit
I _I	Input pin	$V_I = 0 V \text{ to } V_{CCIOMAX}$	-30	_	30	μA
I _{OZ}	Tri-stated I/O pin	$V_0 = 0 V \text{ to } V_{\text{CCIOMAX}}$	-30		30	μA

Note to Table 9:

(1) If $V_0 = V_{CCI0}$ to $V_{CCI0Max}$, 100 μ A of leakage current per I/O is expected.

Bus Hold Specifications

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

				V _{CCI0}									
Parameter	Symbol	Conditions	1.2	2 V	1.	5 V	1.8	B V	2.5	5 V	3.0	V	Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I _{SUSL}	V _{IN} > V _{IL} (maximum)	22.5	_	25.0	_	30.0	_	50.0	_	70.0	_	μA
High sustaining current	I _{SUSH}	V _{IN} < V _{IH} (minimum)	-22.5		-25.0	_	-30.0	_	-50.0	_	-70.0		μA
Low overdrive current	I _{odl}	$0V < V_{IN} < V_{CCIO}$		120		160		200	_	300		500	μA
High overdrive current	I _{odh}	$0V < V_{IN} < V_{CCIO}$		-120		-160		-200		-300		-500	μΑ
Bus-hold trip point	V _{TRIP}	_	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	۷

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices ⁽¹⁾ (Part 1 of 2)

			Calibration Accuracy				
Symbol	Description	Conditions	C1	C2,I2	C3,I3, I3YY	C4,14	Unit
25- $Ω$ R _S	Internal series termination with calibration (25- Ω setting)	V _{CCI0} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

			Calibration Accuracy					
Symbol	Description	Conditions	C1	C2,I2	C3,I3, I3YY	C4,14	Unit	
50-Ω R _S	Internal series termination with calibration (50- Ω setting)	V _{CCI0} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%	
34- Ω and 40- Ω R _S	Internal series termination with calibration (34- Ω and 40- Ω setting)	V _{CCI0} = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%	
48-Ω, 60-Ω, 80-Ω, and 240-Ω R _S	Internal series termination with calibration (48- Ω , 60- Ω , 80- Ω , and 240- Ω setting)	V _{CCI0} = 1.2 V	±15	±15	±15	±15	%	
50-Ω R _T	Internal parallel termination with calibration (50-Ω setting)	V _{CCI0} = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
20-Ω, 30-Ω, 40-Ω,60-Ω, and 120-Ω R _T	Internal parallel termination with calibration ($20 - \Omega$, $30 - \Omega$, $40 - \Omega$, $60 - \Omega$, and $120 - \Omega$ setting)	V _{CCI0} = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
60- $Ω$ and 120- $Ω$ R _T	Internal parallel termination with calibration (60-Ω and 120-Ω setting)	V _{CCI0} = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%	
$25-\Omega \\ R_{S_left_shift}$	Internal left shift series termination with calibration ($25-\Omega$ R _{S_left_shift} setting)	V _{CCI0} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%	

Table II. OUI Valiblation Accuracy specifications for Stratix V Devices' / (Latt 2 OF	Table 11.	OCT Calibration A	ccuracy Specificati	ons for Stratix V D	Devices ⁽¹⁾ (Part 2 of
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Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance to PVT changes.

Table 12.	OCT Without Calibration	Resistance 1	Tolerance	Specifications	for Stratix	V Devices	(Part 1	of 2)
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			Resistance Tolerance				
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit
25-Ω R, 50-Ω R _S	Internal series termination without calibration (25-Ω setting)	$V_{CCIO} = 3.0$ and 2.5 V	±30	±30	±40	±40	%
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCI0} = 1.8 and 1.5 V	±30	±30	±40	±40	%
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCI0} = 1.2 V	±35	±35	±50	±50	%

Symbol	Description	V _{CCIO} (V)	Typical	Unit			
dR/dT		3.0	0.189				
		2.5	0.208				
	OCT variation with temperature without recalibration	1.8	0.266	%/°C			
	without robalibration	1.5	0.273]			
		1.2	0.317	1			

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2)⁽¹⁾

Note to Table 13:

(1) Valid for a V_{CCIO} range of $\pm 5\%$ and a temperature range of 0° to 85°C.

Pin Capacitance

Table 14 lists the Stratix V device family pin capacitance.

Table 14. Pin Capacitance for Stratix V Devices

Symbol	Description	Value	Unit
CIOTB	Input capacitance on the top and bottom I/O pins	6	pF
C _{IOLR}	Input capacitance on the left and right I/O pins	6	рF
C _{OUTFB}	Input capacitance on dual-purpose clock output and feedback pins	6	pF

Hot Socketing

Table 15 lists the hot socketing specifications for Stratix V devices.

Symbol	Description	Maximum
I _{IOPIN (DC)}	DC current per I/O pin	300 μA
I _{IOPIN (AC)}	AC current per I/O pin	8 mA ⁽¹⁾
IXCVR-TX (DC)	DC current per transceiver transmitter pin	100 mA
IXCVR-RX (DC)	DC current per transceiver receiver pin	50 mA

Note to Table 15:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{10PIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

Symbol	Description	V _{CCIO} Conditions (V) ⁽³⁾	Value ⁽⁴⁾	Unit		
		3.0 ±5%	25	kΩ		
		2.5 ±5%				
	Value of the I/O pin pull-up resistor before	1.8 ±5%	25	kΩ		
R _{PU}	and during configuration, as well as user mode if you enable the programmable	1.5 ±5%	25	kΩ		
	pull-up resistor option.	1.35 ±5%	25	kΩ		
		1.25 ±5%	25	kΩ		
		1.2 ±5%	25	kΩ		

Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices (1), (2)

Notes to Table 16:

(1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.

(2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 k Ω .

- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (4) These specifications are valid with a $\pm 10\%$ tolerance to cover changes over PVT.

I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V_{IH} and V_{IL}), output voltage (V_{OH} and V_{OL}), and current drive characteristics (I_{OH} and I_{OL}) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL}, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to "Glossary" on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012_486.

I/O	V _{CCIO} (V)		V _{IL} (V)		V _{IH} (V)		V _{OL} (V)	V _{OH} (V)	I _{OL}	I _{oh}	
Standard	Min	Тур	Max	Min	Max	Min	Max	Max	Min	(mA)	(mA)
LVTTL	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.4	2.4	2	-2
LVCMOS	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.2	$V_{CCIO} - 0.2$	0.1	-0.1
2.5 V	2.375	2.5	2.625	-0.3	0.7	1.7	3.6	0.4	2	1	-1
1.8 V	1.71	1.8	1.89	-0.3	0.35 * V _{CCIO}	0.65 * V _{CCIO}	V _{CCI0} + 0.3	0.45	V _{CCI0} – 0.45	2	-2
1.5 V	1.425	1.5	1.575	-0.3	0.35 * V _{CCI0}	0.65 * V _{CCI0}	V _{CCI0} + 0.3	0.25 * V _{CCIO}	0.75 * V _{CCIO}	2	-2
1.2 V	1.14	1.2	1.26	-0.3	0.35 * V _{CCI0}	0.65 * V _{CCI0}	V _{CCI0} + 0.3	0.25 * V _{CCIO}	0.75 * V _{CCIO}	2	-2

Table 17. Single-Ended I/O Standards for Stratix V Devices

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 6 of 7)

Symbol/	Conditions	Trai	nsceive Grade	r Speed 1	Trar	isceive Grade	r Speed 2	Tran	Unit			
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max		
Inter-transceiver block transmitter channel-to- channel skew	xN PMA bonded mode	_	_	500	— — 500		500	_	_	500	ps	
CMU PLL										•		
Supported Data Range	_	600	_	12500	600	_	12500	600	_	8500/ 10312.5 (24)	.5 Mbps	
t _{pll_powerdown} ⁽¹⁵⁾	—	1			1			1			μs	
t _{pll_lock} ⁽¹⁶⁾	L_lock ⁽¹⁶⁾			10	—	_	10	—	_	10	μs	
ATX PLL												
	VCO post-divider L=2	8000	_	14100	8000	_	12500	8000	_	8500/ 10312.5 (24)	Mbps	
Supported Data	L=4	4000	_	7050	4000	_	6600	4000	—	6600	Mbps	
Rate Range	L=8	2000		3525	2000		3300	2000		3300	Mbps	
	L=8, Local/Central Clock Divider =2	1000	_	1762.5	1000	_	1762.5	1000	_	1762.5	Mbps	
t _{pll_powerdown} (15)	—	1	_	—	1	_	—	1	_	—	μs	
t _{pll_lock} (16)	—		—	10		—	10	—		10	μs	
fPLL	•									•		
Supported Data Range	_	600	_	3250/ 3125 ⁽²⁵⁾	600	_	3250/ 3125 ⁽²⁵⁾	600	_	3250/ 3125 ⁽²⁵⁾	Mbps	
t _{pll_powerdown} ⁽¹⁵⁾	_	1	—		1	—		1			μs	

Table 26 shows the approximate maximum data rate using the 10G PCS.

Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32			
mode ""	Speed Grade	PCS Width	64	66/67	50	40	64/66/67	32			
	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6			
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5			
		C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88			
FIFO or Register	3	C1, C2, C2L, I2, I2L core speed grade	8.5 Gbps								
		C3, I3, I3L core speed grade									
		C4, I4 core speed grade									
		I3YY core speed grade	10.3125 Gbps								

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.





Figure 3 shows the Stratix V AC gain curves for GX channels.

Figure 3. AC Gain Curves for GX Channels (full bandwidth)

Stratix V GT devices contain both GX and GT channels. All transceiver specifications for the GX channels not listed in Table 28 are the same as those listed in Table 23.

Table 28 lists the Stratix V GT transceiver specifications.

Symbol/	Conditions	s	Transceive peed Grade	r 2	S	Unit					
Description		Min	Тур	Max	Min	Тур	Max				
Reference Clock								1			
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCN	IL, 1.4-V PC	ML, 1.5-V P(CML, 2.5-V I and HCSL	PCML, Diffe	rential LVPE	ECL, LVDS,			
otanuarus	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS									
Input Reference Clock Frequency (CMU PLL) ⁽⁶⁾		40	_	710	40	_	710	MHz			
Input Reference Clock Frequency (ATX PLL) ⁽⁶⁾	_	100	_	710	100	_	710	MHz			
Rise time	20% to 80%	_		400	_	_	400				
Fall time	80% to 20%			400	—	_	400	ps			
Duty cycle	—	45	_	55	45	_	55	%			
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	_	33	30	_	33	kHz			
Spread-spectrum downspread	PCle	_	0 to -0.5	_	_	0 to -0.5	_	%			
On-chip termination resistors ⁽¹⁹⁾	_	_	100	_	_	100	_	Ω			
Absolute V _{MAX} ⁽³⁾	Dedicated reference clock pin	_	_	1.6	_	_	1.6	V			
	RX reference clock pin	_	_	1.2	_	_	1.2				
Absolute V _{MIN}	—	-0.4		—	-0.4	—		V			
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	mV			
V _{ICM} (AC coupled)	Dedicated reference clock pin		1050/1000 ^{(,}	2)	1	050/1000 (2)	mV			
	RX reference clock pin	1	.0/0.9/0.85 (22)	1.	V					
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	_	550	250	_	550	mV			

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5)⁽¹⁾

Figure 4 shows the differential transmitter output waveform.





Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85° C) and the industrial junction temperature range (-40° to 100° C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5		800 (1)	MHz
f _{IN}	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5		800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 ⁽¹⁾	MHz
f _{INPFD}	Input frequency to the PFD	5	—	325	MHz
f _{FINPFD}	Fractional Input clock frequency to the PFD	50	—	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f _{VCO} (9)	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600		1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
t _{einduty}	Input clock or external feedback clock input duty cycle	40	—	60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	_	_	717 ⁽²⁾	MHz
f _{out}	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)			650 ⁽²⁾	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)			580 ⁽²⁾	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)			800 ⁽²⁾	MHz
f _{OUT_EXT}	Output frequency for an external clock output (C3, I3, I3L speed grades)			667 ⁽²⁾	MHz
	Output frequency for an external clock output (C4, I4 speed grades)			553 ⁽²⁾	MHz
t _{outduty}	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
t _{FCOMP}	External feedback clock compensation time	_		10	ns
f _{dyconfigclk}	Dynamic Configuration Clock used for mgmt_clk and scanclk		_	100	MHz
t _{LOCK}	Time required to lock from the end-of-device configuration or deassertion of areset			1	ms
t _{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)			1	ms
	PLL closed-loop low bandwidth	—	0.3	—	MHz
f _{CLBW}	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth (7)	—	4	-	MHz
t _{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t _{ARESET}	Minimum pulse width on the areset signal	10	—	_	ns

Symbol	Conditiono		C1		C2,	C2, C2L, I2, I2L		C3, I3, I3L, I3YY			C4,I4			Unit
Symbol	Conutions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
Transmitter														
True Differential I/O Standards - f _{HSDR} (data rate)	SERDES factor J = 3 to 10 ⁽⁹⁾ , ⁽¹¹⁾ , ⁽¹²⁾ , ⁽¹³⁾ , ⁽¹⁴⁾ , ⁽¹⁵⁾ , ⁽¹⁶⁾	(6)	_	1600	(6)	_	1434	(6)	_	1250	(6)	_	1050	Mbps
	SERDES factor J ≥ 4 LVDS TX with DPA (12), (14), (15), (16)	(6)		1600	(6)		1600	(6)		1600	(6)	_	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)		(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f _{HSDR} (data rate) ⁽¹⁰⁾	SERDES factor J = 4 to 10 $(^{17})$	(6)		1100	(6)		1100	(6)		840	(6)		840	Mbps
t _{x Jitter} - True Differential	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps		_	160		_	160		_	160			160	ps
I/O Standards	Total Jitter for Data Rate < 600 Mbps		_	0.1			0.1			0.1		_	0.1	UI
t _{x Jitter} - Emulated Differential I/O Standards with Three External Output Resistor Network	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_	_	300	_	_	300	_	_	300	_		325	ps
	Total Jitter for Data Rate < 600 Mbps	_	_	0.2	_	_	0.2	_	_	0.2	_	_	0.25	UI

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 2 of 4)

	0		C1		C2,	C2L, I	2, I2L	C3,	13, 131	., I 3YY		C4,I	4	
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
t _{duty}	Transmitter output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	45	50	55	%
	True Differential I/O Standards	_	_	160	_	_	160	_	_	200	_	_	200	ps
t _{rise} & t _{fall}	Emulated Differential I/O Standards with three external output resistor networks			250			250			250			300	ps
	True Differential I/O Standards	_	_	150	_	_	150	_	_	150	_	_	150	ps
TCCS	Emulated Differential I/O Standards			300			300	_		300			300	ps
Receiver														
	SERDES factor J = 3 to 10 (11), (12), (13), (14), (15), (16)	150		1434	150	_	1434	150	_	1250	150	_	1050	Mbps
True Differential 1/0 Standards	SERDES factor J ≥ 4 LVDS RX with DPA (12), (14), (15), (16)	150	_	1600	150	_	1600	150	_	1600	150	_	1250	Mbps
- f _{HSDRDPA} (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)		(7)	Mbps

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 3 of 4)

Jitter Free	quency (Hz)	Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

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Figure 9 shows the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate < 1.25 Gbps.





DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

Table 39. DLL Range Specifications for Stratix V Devices (1)

C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
300-933	300-933	300-890	300-890	MHz

Note to Table 39:

(1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

Speed Grade	Min	Max	Unit
C1	8	14	ps
C2, C2L, I2, I2L	8	14	ps
C3,I3, I3L, I3YY	8	15	ps

Clock	Parameter	Symbol	C	1	C2, C2L	, 12, 12L	C3, I3 I3	8, 13L , YY	C4	,14	Unit
NELWUIK		-	Min	Max	Min	Max	Min	Max	Min	Max	
	Clock period jitter	$t_{JIT(per)}$	-25	25	-25	25	-30	30	-35	35	ps
PHY Clock	Cycle-to-cycle period jitter	$t_{\rm JIT(cc)}$	-50	50	-50	50	-60	60	-70	70	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-37.5	37.5	-37.5	37.5	-45	45	-56	56	ps

Table 42. Memory Output Clock Jitter Specification for Stratix V Devices (1), (Part 2 of 2) (2), (3)

Notes to Table 42:

(1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.

(2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.

(3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

OCT Calibration Block Specifications

Table 43 lists the OCT calibration block specifications for Stratix V devices.

Table 43. OCT Calibration Block Specifications for Stratix V Devices

Symbol	Description	Min	Тур	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	_	20	MHz
T _{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT $\rm R_S/R_T$ calibration		1000	_	Cycles
T _{OCTSHIFT}	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	_	32	_	Cycles
T _{RS_RT}	Time required between the dyn_term_ctrl and oe signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (Figure 10)		2.5		ns

Figure 10 shows the timing diagram for the oe and dyn_term_ctrl signals.

Figure 10. Timing Diagram for oe and dyn_term_ctrl Signals



Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

Table 44. Worst-Case DCD on Stratix V I/O Pins (1)

Symbol	C	1	C2, C2	L, 12, 12L	C3, I I3	3, I3L, BYY	C4	4,14	Unit
-	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

Configuration Specification

POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

Table 45. Fast and Standard POR Delay Specification (1)

POR Delay	Minimum	Maximum
Fast	4 ms	12 ms
Standard	100 ms	300 ms

Note to Table 45:

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t _{JCP}	TCK clock period ⁽²⁾	30		ns
t _{JCP}	TCK clock period ⁽²⁾	167	—	ns
t _{JCH}	TCK clock high time ⁽²⁾	14	—	ns
t _{JCL}	TCK clock low time ⁽²⁾	14		ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2	—	ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3	_	ns

Table 60. Glossary (Part 2 of 4)

Letter	Subject	Definitions
G H I	JTAG Timing Specifications	High-speed I/O block—Deserialization factor (width of parallel data bus). JTAG Timing Specifications: TMS
K L M N O		
Ρ	PLL Specifications	Diagram of PLL Specifications ⁽¹⁾
Q	—	—
R	RL	Receiver differential input discrete resistor (external to the Stratix V device).

Document Revision History

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes
June 2018	3.9	 Added the "Stratix V Device Overshoot Duration" figure.
		Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.
		 Changed the minimum value for t_{CD2UMC} in the "PS Timing Parameters for Stratix V Devices" table.
		 Changed the condition for 100-Ω R_D in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table.
April 2017	3.8	 Changed the minimum value for t_{CD2UMC} in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table.
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table.
		 Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table.
June 2016	2.7	 Added the V_{ID} minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table
Julie 2010	5.7	 Added the I_{OUT} specification to the "Absolute Maximum Ratings for Stratix V Devices" table.
December 2015	3.6	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.
December 2015	2.5	 Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table.
December 2015	3.5	 Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table.
		• Changed the data rate specification for transceiver speed grade 3 in the following tables:
		 "Transceiver Specifications for Stratix V GX and GS Devices"
		 "Stratix V Standard PCS Approximate Maximum Date Rate"
		 "Stratix V 10G PCS Approximate Maximum Data Rate"
July 2015	3.4	 Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table.
		 Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table.
		 Changed the t_{c0} maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table.
		 Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table.